

Fig 1. SEM Image (Magnification x 130) of Onyx ESD specimen corner before and after exposure to ground simulation of VLEO environment (STARLINK-11193, 2 years operation)

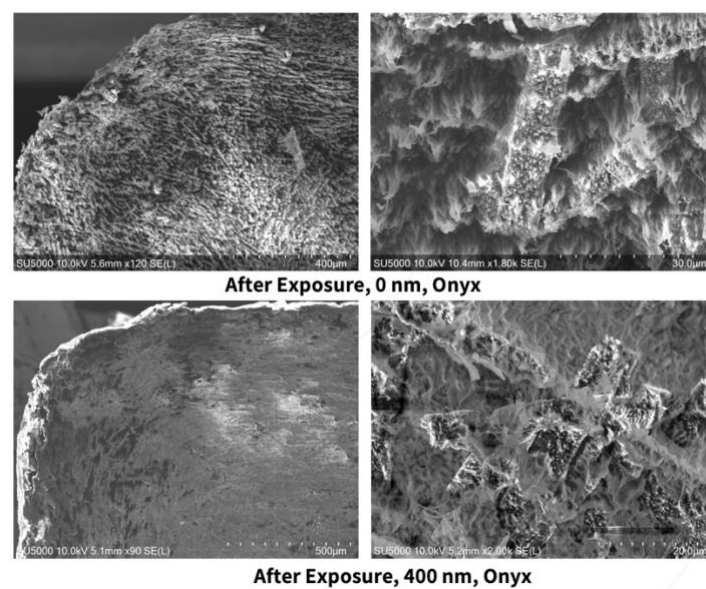


Fig 2. SEM Image of Onyx Specimen corner before and after exposure to ground simulation of VLEO environment (STARLINK-11193, 2 years operation): 0 nm SiO₂ coating (top) and 400 nm SiO₂ coating (bottom)